

Search Notes

Application/Control No.

10/802,734

Examiner

Jim Vannucci

Applicant(s)/Patent under
Reexamination

BEHFAR ET AL.

Art Unit

2828

SEARCHED

| Class | Subclass | Date | Examiner |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| etched gap, dbr, laser, facet | 1/3/2005 | JV |
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